

Foreword

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In this issue...

In this issue of *SRB*, we have an article on an innovative new method of scoring yes/no vocabulary tests, a timely and relevant paper on the reliability of the TOEIC Bridge, an introduction to a fantastic piece of free statistics software, an interview with one of the most interesting people in language testing today, and, of course, another installment of JD Brown's indispensable statistics column. We also have a new section where we feature the recent publications of the TEVAL SIG members, as well as the customary list of upcoming language testing events. Personally, I am glad to present such a strong issue to the TEVAL SIG membership at this time because...

A fond farewell... again

Due to my acceptance to a language-testing-related PhD program, as well as expanding teaching and research commitments, I am sorry to report that this is my last issue of *SRB* as General Editor. I have really enjoyed this position, and I am proud of the work I have done. I have worked hard to modernize this publication over the last year, and have made some real progress in that regard—progress that will continue under the next General Editor, my personal pick for the position: the astoundingly diligent and capable Jeffrey Stewart, whom I have been privileged to have as my Associate Editor for this past year. As Jeff has been my partner in all the editorial decisions of the past year, the direction of the publication will continue on its current course under his editorship. I will, of course, continue to support the publication as a member of the editorial committee. Unfortunately, however, I will just be too busy for the next few years to devote the time and attention necessary to deliver the caliber of publication that I think TEVAL deserves. Thanks for the support over the last year, and I am sure you will offer the same to Jeff.

We hope you enjoy this issue of *SRB*.